

# A Low Power Inductorless LNA With Double $G_m$ Enhancement in 130 nm CMOS

François Belmas, Frédéric Hameau, and Jean-Michel Fournier

**Abstract**—This paper presents the design of a low power differential Low Noise Amplifier (LNA) in 130 nm CMOS technology for 2.45 GHz ISM band applications. The circuit benefits from several  $g_m$ -enhancements. These techniques provide a high gain and reduced Noise Figure (NF) in spite of the low intrinsic  $g_m$  of the MOS transistors. Moreover, the circuit is fully inductorless. Main design points are described and the performance tradeoffs of the circuit are discussed. A prototype has been implemented and it exhibits a 20 dB gain with a 4 dB NF while dissipating 1.32 mW. The  $IIP_3$  is  $-12$  dBm for an input compression point of  $-21$  dBm.

**Index Terms**—Inductorless, ISM band, LNA, low power, 245 GHz.

## I. INTRODUCTION

WIRELESS Sensor Network (WSN) standards like IEEE 802.15.4 require drastically low active mode power consumption ( $P_{DC}$ ) for remote applications with long battery lifetime. The particular case of WSN apin the 2.45 GHz ISM band usually leads to RF Integrated Circuits (RFICs) using LNAs circuit with multiple inductors. These bulky inductors result in expensive RFIC [1]. Removing them is definitely a cost effective approach. Conversely, low  $P_{DC}$  inductorless LNAs cannot offer the narrowband and low Noise Figure (NF) of their inductor-based counterparts. Designing such low cost circuits is then very challenging. To be relevant for a WSN application, inductorless LNAs should provide a large voltage gain (given the low  $g_m$  values available) as well as drastically reduced silicon area. Additionally, RFIC SoC architectures must handle the increased NF and the inherent wideband nature of such inductorless LNA. This work proposes an inductorless LNA suitable for 2.45 GHz ISM band WSN applications with a milliwatt range  $P_{DC}$ . We focus on LNA design with  $g_m$ -boost techniques [2], [3]. These techniques have been widely used in common gate LNAs where  $P_{DC}$  is a key point as in [4]. More recently, some papers investigated the benefit of “active”  $g_m$ -boost techniques applied to LNAs [5], [6]. We push further the investigation in order to reach the highest possible voltage gain with a NF as low as possible. For that, a new doubly  $g_m$ -boosted differential LNA is presented [7]. The combination of gain, noise and bandwidth improvement techniques

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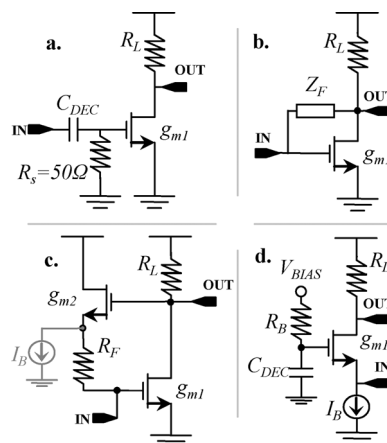


Fig. 1. Inductorless LNAs : a. Resistive matched LNA, b. Impedance-based SFB LNA, c. Source-follower-based SFB LNA, d. Basic CG LNA.

offers a good global performance tradeoff. While keeping a very low  $P_{DC}$ , the circuit is fully differential for an easier SoC integration. This paper is organized as follow: Section II details the known design techniques of inductorless LNAs. The proposed circuit is presented in Section III. In addition to [7], we detail more deeply the input matching as well as gain, bandwidth, linearity, noise, and stability. Finally, part IV presents experimental results.

## II. BACKGROUND IN INDUCTORLESS LNA DESIGN

Inductorless LNA design is mainly based on circuit techniques for low input impedance while maintaining good gain and noise performance. The difficulty lies on the generation of mainly real impedance while a MOS transistor exhibits generally capacitive high input impedance. A straightforward solution could be a discrete matching using a  $50 \Omega$  input shunt resistance Fig. 1(a) bounding the NF to 3 dB in conflict with low noise goals. A more acute approach points to circuits either based on shunt feedback (SFB) amplifiers or common gate (CG) topology. Schematics of these structures are given in (Fig. 1) and their performance metrics are summarized in Table I.

### A. Shunt Feedback Technique

The impedance-based SFB amplifier (Fig. 1(b)) provides real input matching using feedback impedance. It generally consists of either a pure resistance  $Z_F = R_F$  [8] or a parallel tank  $Z_F = R_F // C_F$  [9]. In any case, the input matching is obtained thanks to the LNA voltage gain  $G_V$ . The degraded output impedance ( $Z_F // R_L$ ) is a major drawback of impedance based SFB amplifiers. Indeed, this limitation enforces larger  $g_m$  value when higher gain is targeted and thus  $P_{DC}$  increases.

TABLE I  
BASIC EQUATIONS OF KNOWN INDUCTORLESS LNA CIRCUITS OF FIG. 1

LNA Circuit	Impedance based SFB [8]	Source Follower based SFB [11]	CG [10]
Voltage Gain	$G_V = -\frac{g_{m1} - g_F}{g_L + g_F}$	$G_V = -g_{m1}R_L$	$G_V = +g_{m1}R_L$
Input Admittance $Y_{IN} = 1/Z_{IN}$	$Y_{IN} = g_F(1 - A_V)$	$Y_{IN} = \frac{g_{m2}}{1 + g_{m2}R_F} (1 - A_V)$ $g_{m2Eq}$	$Y_{IN} = g_{m1}$
Matching Condition (M.C)	$R_F = (g_{m1}R_L + 1)R_S - R_L$	$g_{m2Eq} = R_S^{-1}(1 - A_V)^{-1}$	$g_{m1} = R_S^{-1}$
$F_{nm}^{(*)}$ (Noise Factor without M.C)	$1 + \frac{NEF_1}{g_{m1}R_S} + \frac{4R_S}{R_F} \left( \frac{(1 + g_{m1}R_S)R_L}{(1 + g_{m1}R_S)R_L + R_F + R_S} \right)^2$ $+ \frac{1}{R_S R_L g_{m1}^2}$	$1 + \frac{NEF_1}{g_{m1}R_S} (R_S^{-1} + g_{m2Eq})^2 + g_{m2Eq}^2 R_F R_S$ $+ \frac{1}{R_S R_L g_{m1}^2} (R_S^{-1} + g_{m2Eq})^2$	$1 + \frac{NEF_1}{g_{m1}R_S} + \frac{R_S}{R_L} \left( 1 + \frac{1}{g_{m1}R_S} \right)^2$
$F_n^{(*)}$ (Noise Factor with M.C)	$1 + \frac{NEF_1}{g_{m1}R_S} + \frac{(1 + (g_{m1}R_S)^{-1})^2}{(g_{m1}R_L + 1) - R_L/R_S} + \frac{1}{R_S R_L g_{m1}^2}$	$1 + \frac{NEF_1}{g_{m1}R_S} + \frac{R_F}{R_S(1 + A_V)^2} + \frac{1}{R_S R_L g_{m1}^2}$	$1 + NEF_1 + \frac{4R_S}{R_L}$

(\*) It assumes a MOS drain current noise PSD expressed as  $4kT \cdot NEF_1 \cdot g_m \cdot \Delta f$ , with  $NEF_1$  the Noise Excess Factor as it is defined in [15].

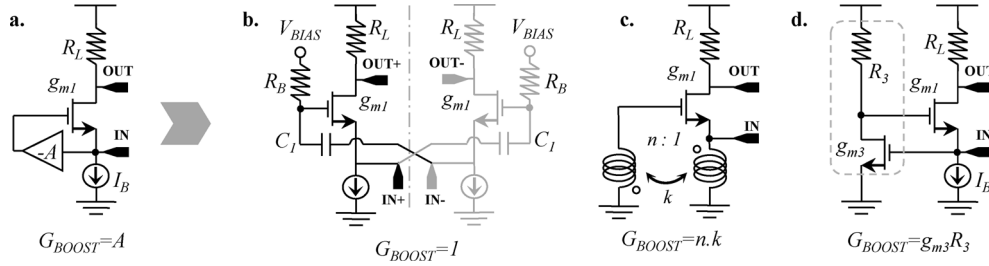


Fig. 2.  $G_m$ -boosted LNA a. generic  $g_m$ -boost CG, b. Differential CCC LNA, c. Transformer based  $g_m$ -boost, d. CS based  $g_m$ -boost circuit.

For that, [11] proposed a feedback circuit with a degenerated source follower (Fig. 1(c)). Although extra  $P_{DC}$  is required for the feedback, it efficiently decouples the output from the input impedance. Authors in [11] detail the underlying linearity-gain tradeoff inherent to such source-follower-based SFB circuits. As in [11] and [12], it is commonly known that the SFB amplifiers, whatever the feedback type, exhibit poor NF and poor linearity performance when  $g_m$  values are very low (i.e., few mS). Note that some more elaborate feedbacks based on multi-stage [13] or current-reuse [14] can slightly improve the linearity-gain tradeoff while keeping the same basic approach.

### B. Common Gate (CG) Technique

The main alternative to SFB amplifiers is the CG topology (Fig. 1(d)). The basic CG circuit benefits from the  $1/g_m$  source terminal impedance. It follows that the amplifying  $g_m$  simultaneously sets the gain and the input impedance. The input matching condition  $g_{m1}R_S = 1$  results in a matched noise factor limited to  $1 + NEF_1$  where  $NEF_1$  is the noise excess factor of the MOS transconductance  $g_{m1}$  [15]. For this reason, CG circuits are considered noisy regarding SFB amplifiers where  $g_{m1}R_S$  can be much larger than unity (Table I). CG circuits still have some advantages. First, they have a better linearity as they exhibit a low input voltage gain. Another difference between CG and SFB circuits concerns the available accessibility of the gate terminal. In fact, this node does not need to be a pure DC node for correct operation. This statement leads to a class of circuits called  $g_m$ -boost CG circuits [2], [4] which are usually dedicated to low power operation.

### C. $G_m$ -Boost Technique

The basics of  $g_m$ -boost techniques consist of applying simultaneously the signal on both gate and source pins to increase the  $v_{GS}$  swing on the MOS transistor (Fig. 2).

The technique requires an auxiliary voltage gain ( $G_{BOOST}$ ) aside from the CG circuit (Fig. 2(a)). Assuming an ideal boosting amplifier, the obtained LNA metrics are reported in (Table II). This technique enables a reduction of the noise factor ( $F$ ) while simultaneously offering a favorable  $P_{DC}$ -matching tradeoff. This approach is very popular in differential LNA design [4], [10]. Indeed, a  $g_m$ -boosting effect is simply enabled through a Capacitive Cross Coupling (CCC – Fig. 2(b)) of the inputs at no  $P_{DC}$  costs. However, the improvement of the  $P_{DC}$ -matching tradeoff is somewhat limited: since the CCC is based on a passive amplification, it limits  $G_{BOOST}$  to values lower than 1. One could address that point through the use of an inductive transformer (Fig. 2(c)) [3] but a large extra silicon area will be required. The last solution involves an auxiliary active amplifier, a CS stage for instance, with a dedicated  $P_{DC}$  budget [5] (Fig. 2(d)). To improve performance in such actively-boosted CG LNA, both main and auxiliary amplifiers must be power-optimized. The  $g_m$ -boosting amplifier in previous works ([5], [6] & [16]) always shows high input impedance. A design of this amplifier with a finite input impedance would relax even more the  $P_{DC}$ -matching tradeoff. Indeed, the boosting amplifier will then reduce the input impedance not only through its own gain ( $G_{BOOST}$ ) but also through its finite input impedance. Furthermore, nothing forbids the use of  $g_m$ -boosting techniques inside the auxiliary

TABLE II  
GENERIC METRICS IMPROVEMENT IN  $g_m$ -BOOSTED CG LNA

LNA Metrics	$G_m$ -boosted LNA—Single Ended Case with $G_{BOOST}=A$
Gain	$G_V = -g_{m1}RL(1+A)$
$Y_{IN}=1/Z_{IN}$	$Y_{IN} = g_{m1}(1+A)$
Matching condition	$g_{m1}R_S(1+A) = 1$
$(F_{um}, F_m) \approx$	$F_{um} = 1 + \frac{NEF_1}{(1+A)^2 g_{m1}R_S}$ $F_m = 1 + \frac{NEF_1}{(1+A)}$
IIP <sub>3</sub>	$\approx \text{IIP}_{3(CG \text{ No Boost})}/(1+A)$

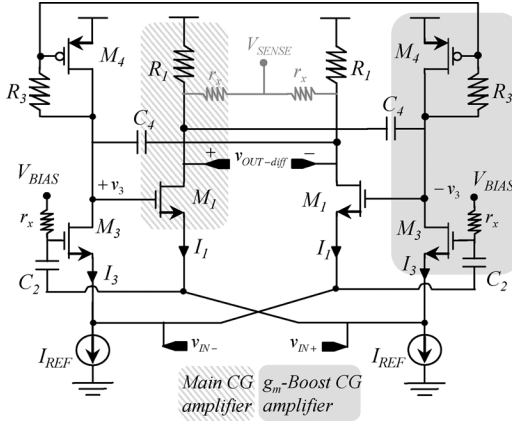


Fig. 3. Schematic of the proposed differential CGAB LNA circuit.

amplifier circuit in order to reduce its  $P_{DC}$  budget. In the following section we propose a  $g_m$ -boosted LNA that consider these two remarks.

### III. PROPOSED COMMON GATE ACTIVE BOOST LNA

#### A. Basic Idea

The proposed circuit is depicted in Fig. 3 and includes a CG circuit being  $g_m$ -boosted through another CG circuit rather than a CS. The “main CG amplifier”, made with  $M_1$  and  $R_1$ , is enhanced by the “ $g_m$ -boost amplifier” made with  $M_3$  and  $R_3$ . A CCC technique is added to the boosting amplifier ( $C_2$  MOM capacitor). It further enhances its gain and reduces its noise. The boosting gain is therefore doubled without extra  $P_{DC}$  and becomes  $G_{BOOST} \approx 2g_{m3}R_3$ .

The obtained Common Gate Active Boost LNA (CGAB) is thus a double- $g_m$ -enhanced LNA. Moreover, the finite input impedance at the source terminal of  $M_3$  is a novel degree of freedom to define the LNA input impedance. Using a CG circuit, known to be more linear than a CS circuit [2], helps to improve the linearity of the whole LNA at low  $P_{DC}$  where low bias current usually degrades linearity. The proposed circuit also involves a capacitive coupling of both CG circuit’s outputs through  $C_4$  capacitance for bandwidth enhancement. The active load made by  $M_4$  avoids large DC voltage drop through  $R_3$ . Both  $M_4$  gates are connected together to form a dynamic ground. This connection disables the parasitic active inductor at node  $v_3$  which is mainly created by  $M_4$  gate capacitor. Since this inductance is usually large, it results in an unwanted low frequency gain resonance. The DC current of both amplifiers is shared in a common input current source and  $I_{REF} = I_1 + I_3$  in order to avoid extra input current mirror. The  $I_1/I_3$  ratio is set by

$V_{BIAS}$  through a large value resistor  $r_x$  (20 k $\Omega$ ) which isolates the biasing parts from the RF parts. It has to be noticed that the  $M_1$  gate is DC coupled and it doesn’t require any extra RC-bias tee. The high-pass cut-off of the  $r_x C_2$  network ( $f_{rx} = 16$  MHz) is neglected hereafter. Finally, it is assumed that the LNA is loaded with a capacitor  $C_L = 50$  fF at each output in the following analysis to model the input capacitance of a succeeding mixer. The circuit is scaled to operate at milliwatt range  $P_{DC}$  ( $< 2$  mW). All active transistors are of minimum gate length (0.13  $\mu\text{m}$ ) and they operate with positive overdrives above saturation limits. Next sections detail the metrics of the LNA of Fig. 3. The various tradeoffs related to the low  $P_{DC}$  and the inductorless aspects are discussed.

#### B. Input Matching

The differential input admittance  $Y_{IN-D}$  is calculated with the MOS small-signal equivalent circuit:  $g_m, g_{DS}, c_{gs}, c_{gd}$ . The low-frequency approximation of  $Y_{IN-D}$  is given in (1) where the two first terms define the low input impedance. The last terms in (1) involving the finite MOS conductances ( $g_{DS1}$  &  $g_{DS3}$ ) are the positive feedbacks proportional to the LNA gain  $G_V$  and the boosting gain  $G_{BOOST}$ . These terms tend to moderately increase the input impedance. They are neglected in the next simplified theory, but they must be considered during circuit design. We neglect  $M_1$  and  $M_3$  transition frequencies  $f_T$ , which are very high compared to the operating frequency

$$Y_{IN-D} = \frac{g_{m1}}{2} (1 + G_{Boost}) + g_{m3} + g_{DS1} (1 - G_V) + g_{DS3} (1 - G_{Boost})$$

$$\Rightarrow Y_{IN-D} \approx \frac{g_{m1}}{2} (1 + 2g_{m3}R_3) + g_{m3} \quad (1)$$

$$Y_{IN-MATCH} = R_S^{-1} \rightarrow g_{m1} \cong \frac{2(1 - g_{m3}R_S)}{R_S(1 + 2g_{m3}R_3)} \quad (2)$$

$$Y_{IN-DIFF-FIG.2d} = R_S^{-1} \rightarrow g_{m1} \cong \frac{2}{R_S(1 + g_{m3}R_3)} \quad (3)$$

A simplified matching condition can be defined and applied to  $g_{m1}$  leading to (2). We compare this with the matching condition (3) obtained for the differential active-boost LNA in Fig. 2(d) ([5], [6]). It results in an improved  $P_{DC}$ -matching tradeoff. The improvement is mainly related to the CCC technique that doubles the boosting gain. We focus now on the input impedance second order effects related to the back-to-back connection of  $M_1$  and  $M_3$ . This topology defines an impedance gyrator which leads to a finite imaginary part in  $Y_{IN-D}$  [17]. A more detailed expression than (1) is obtained from the schematic of Fig. 4 and results in (4) (with  $p = j\omega$ , the Laplace variable)

$$Y_{IN-D} \approx g_{m3} + \frac{g_{m1}}{2} \left( 1 + \frac{2g_{m3}}{g_{33}} \cdot \left( \frac{1}{1 + \frac{(c_{33} + c_{gs1})}{g_{33}} p} \right) \right) \quad (4)$$

In Fig. 4, a simplified load ( $Y_{GATE1}$ ) resulting from  $g_{33}$  in parallel with the equivalent capacitor  $c_{33}$  is used at  $g_m$ -boost amplifier output to simplify the analysis. The evolution of  $Y_{IN-D}$  (4) versus frequency is detailed in Fig. 5 and in Table III, through 3 separate frequency domains (namely **a**, **b** & **c**). At low frequency (**a**)  $Y_{IN-D}$  follows the relation (1), the expected boosted admittance. In (**b**), as  $\omega$  increases close to  $\omega_{LEQ} = g_{33}/(c_{33} + c_{gs1})$ ,



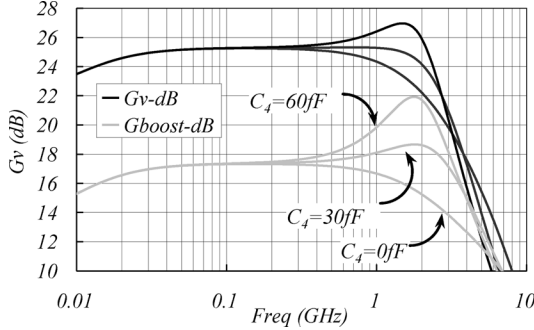


Fig. 7. Simulated  $G_V$  and  $G_{\text{BOOST}}$  for different  $C_4$  values.

The boosting gain impacts the whole LNA gain since we have roughly  $(v_{gs} - M1/v_{in})(p) \cong G_{\text{BOOST}}(p)$ . The purpose of  $C_4$  in such circuits is to act as a neutralizing capacitor which creates a peaking effect by means of positive feedback and extends the bandwidth.  $C_4$  reduces the value of  $\xi$  and also creates an extra zero in  $G_{\text{BOOST}}(p)$  which causes an overshoot effect in the  $G_{\text{BOOST}}(p)$  before the main pole at  $\omega_0$ . Given the tight coupling between both gains the peaking effect helps to increase the whole LNA bandwidth. The maximum gain ( $G_{V-\text{MAX}}$ ) (11) occurs at a resonance frequency (noted  $\omega_R$ ) defined by (12)

$$G_{V-\text{MAX}} = G_{V\text{DC}} \left( 2\xi \sqrt{1 - \xi^2} \right)^{-1} \quad (11)$$

$$\omega_R = \omega_0 \sqrt{1 - 2\xi^2}. \quad (12)$$

Moreover, inspecting (9) to (12), it follows that increasing  $C_4$  increases the overshoot (by decreasing  $\xi$ ) but also decreases  $\omega_0$ . Since we have always  $\omega_R < \omega_0$ , this positive feedback technique is limited and high  $C_4$  values result in early overshoot frequency. The obtained  $G_V$  and  $G_{\text{BOOST}}$  are depicted in Fig. 7. Consequently, the  $C_4$  value must be carefully chosen to extend sufficiently the bandwidth while avoiding the early peaking effect and to limit the in-band gain peaking. The effect of  $C_4$  value on  $\xi$  and ripple is detailed in Fig. 7. With  $C_4 = 30$  fF, the system is critically damped. We choose to implement this value.

The obtained gain peaking is kept small with this capacitance value. The physical implementation of  $C_4$  must not introduce extra parasitic capacitance.

A MOM capacitor without the first metal level is used in this design to obtain the critically damped case of Fig. 7. The layout of  $C_4$  results in enough small parasitic capacitance on node  $v_3$  to be neglected versus the neutralizing effect. Without this bandwidth extension technique we would be forced to reduce output impedance resulting in lower gains and higher noises.

#### D. Noise

The noise factor equation from Table II does not include the contribution from the boosting amplifier. This extra noise will impact the noise-power tradeoff in the circuit. In order to calculate the noise factor, some simplifications are performed to obtain a more insightful equation. First, it is stated that both half-circuit noise sources are correlated. It then implies a fully differential noise voltage at the output with the pessimistic assumption that no common mode cancellation occurs between both half circuits. This statement enables the circuit

simplification detailed in Fig. 8. Both half circuits are thus separated while being driven with two distinct sources, with a  $2R_S$  noise impedance [4]. MOS transistor and resistor thermal noise sources are added to this simplified schematic [15]

$$\overline{i_{M_i}^2} = 4kT (NEF_i) g_{mi} \Delta f \quad (13)$$

$$\overline{i_{R_i}^2} = \left( \frac{4kT}{R_i} \right) \Delta f. \quad (14)$$

Then, each noise transfer function ( $TFn$ ) associated with a given noise source is computed to obtain the noise factor with the definition in (15). The contributions of each noise source are then separated between  $F_{M_3}$ ,  $F_{R_3}$ ,  $F_{M_1}$ ,  $F_{R_1}$  terms forming the complete noise factor  $F$  of the LNA (16)

$$F = 1 + \frac{\overline{i_{R_i}^2} \cdot (TFn_{R_i})^2 + \overline{i_{M_i}^2} \cdot (TFn_{M_i})^2}{4kT \cdot \left( \frac{1}{2R_S} \right) \cdot (TFn_{R_S})^2} \quad (15)$$

$$F = 1 + F_{M_3} + F_{R_3} + F_{M_1} + F_{R_1}. \quad (16)$$

Assuming  $G_{\text{BOOST}} = 2g_{m3}R_3$ ,  $2R_3 \gg R_S$ ,  $2g_{m3}R_3 \gg 1$ , and  $g_{m1,3}R_S \ll 1$ , a simplified noise factor expression  $F_{\text{TOT}}$  is derived (17). It highlights the benefits of using the capacitive cross-coupling technique in the boosting amplifier since it both reduces its noise contribution and doubles the boosting gain. This also improves noise reduction of the main amplifier. The relative contribution of each noise source to  $F_{\text{TOT}}$  versus the chosen  $g_{m3}$  transconductance is detailed in Fig. 9

$$F_{\text{TOT}} \approx 1 + \frac{NEF_3}{2g_{m3}R_S} + \frac{1}{2g_{m3}^2R_3R_S} + \frac{2NEF_1}{g_{m1}R_S(1 + G_{\text{boost}})^2} + \frac{2(1 + g_{m1}R_S(1 + \frac{G_{\text{boost}}}{2}))^2}{g_{m1}^2R_1R_S(1 + G_{\text{boost}})^2}. \quad (17)$$

A constant  $P_{\text{DC}}$  is assumed (i.e., a constant  $I_{\text{REF}} = I_1 + I_3$ ) and therefore when  $g_{m3}$  increases,  $g_{m1}$  decreases. It highlights  $F_{M_3}$  and  $F_{R_3}$  as the main noise contributors. To emphasize the advantage of this technique compared to another actively-boosted LNA design, we derive the noise factor of a differential LNA based on the circuit of Fig. 2(d). ([5], [6]). Using again the simplification process of Fig. 8 we obtain (18). Although  $P_{\text{DC}}$ -matching tradeoffs are different, (17) and (18) can be compared while assuming an identical  $P_{\text{DC}}$ . It follows that the proposed circuit limits more the noise degradation related to the boosting amplifier. The key improvement is related to the extra CCC added into the circuit

$$F_{\text{FIG2D-diff}} \approx 1 + \frac{2NEF_3}{g_{m3}R_S} + \frac{2}{g_{m3}^2R_3R_S} + \frac{2NEF_1}{g_{m1}R_S(1 + g_{m3}R_3)^2} + \frac{(2 + g_{m1}R_S(1 + g_{m3}R_3))^2}{2g_{m1}^2R_1R_S(1 + g_{m3}R_3)^2}. \quad (18)$$

Inspecting Fig. 9 highlights an optimal design point reached when both  $g_{m3}$  and  $g_{m1}$  are bigger than 3 mS. Finally our model (17) is compared to NF simulation of the LNA using the BSIM v3.3 MOS transistor model (Fig. 10). It appears that (17) predicts correctly the simulation result. Moreover, the optimal noise is obtained for an acceptable power matching

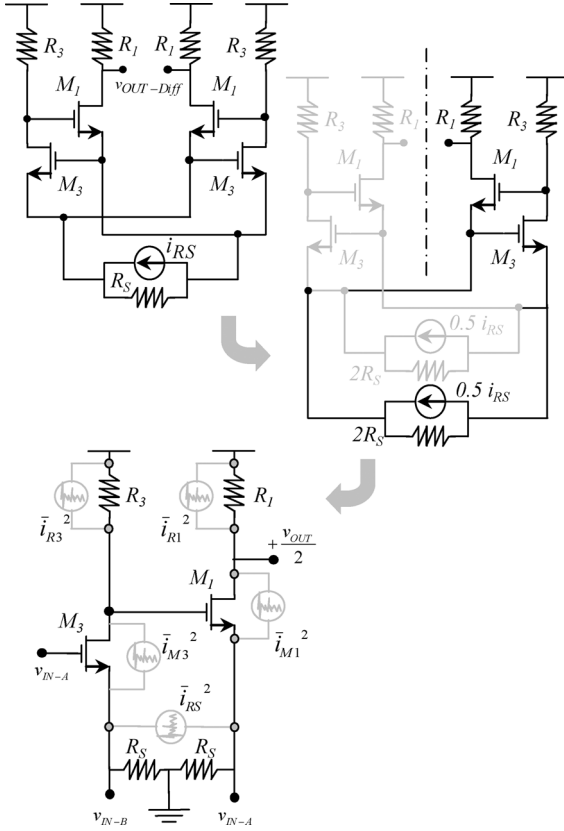


Fig. 8. Circuit simplification to compute the noise figure assuming correlated noise sources of each half-circuit.

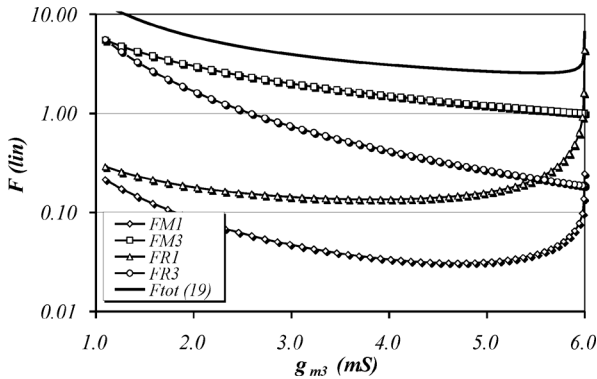


Fig. 9. Noise contributor to  $F_{TOT}$  versus  $g_{m3}$  at constant power consumption.

( $S_{11} < -10$  dB). The proposed circuit shows an acceptable NF for WSN applications. The noise- $P_{DC}$  tradeoff is kept good, even at low  $g_{m3}$  values.

### E. Linearity

The  $g_m$ -boosting block increases the  $v_{gs}$  swing on  $M_1$  enabling the noise reduction highlighted above. On the other hand, the increased voltage swing increases the  $g_m$  related distortion by  $M_1$ . It is worth mentioning that the boosting amplifier also introduces its own extra distortion. Authors in [5] proposed an estimation of the  $g_m$ -boosted LNA  $IIP_3$  using  $IIP_3$  and  $IIP_2$  of both main and  $g_m$ -boosting amplifiers (19). If we assume that both  $IIP_{2-CG}$  and  $IIP_{2-BOOST}$  are very high given the differential implementation, and that  $G_{BOOST}/(1 + G_{BOOST}) \approx 1$ ,

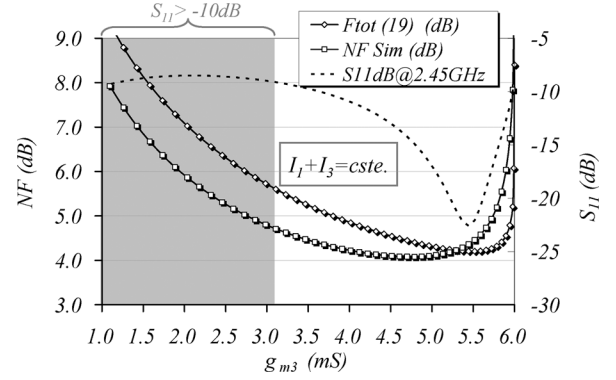


Fig. 10. Equation (17) and simulated NF versus  $g_{m3}$  value.

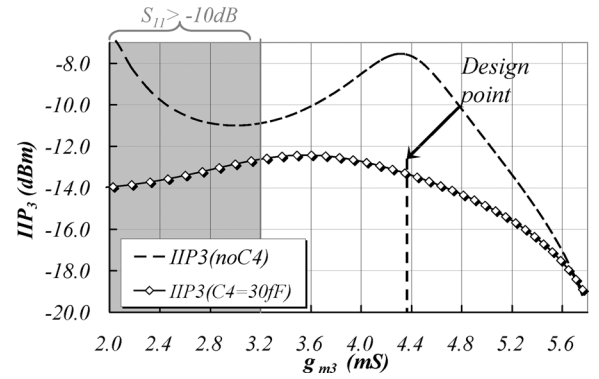


Fig. 11. Simulated  $IIP_3$  at 2.45 GHz of the LNA versus  $g_{m3}$  at constant PDC.

it follows that the  $IIP_3$  is lower than the non-boosted  $IIP_3$  of the main CG circuit ( $IIP_{3-CG}$ ) divided by a factor  $(1 + G_{BOOST})$

$$\frac{1}{IIP_3^2} = \frac{(1 + G_{BOOST})^2}{IIP_{3-CG}^2} + \frac{G_{BOOST}}{(1 + G_{BOOST}) IIP_{3-BOOST}^2} + \frac{3}{2} \cdot \frac{G_{BOOST}}{IIP_{2-CG} \cdot IIP_{2-BOOST}}. \quad (19)$$

The performance scaling of CGAB LNA thus includes a noise-linearity tradeoff since a high boosting gain is necessary for low NF but leads to a degraded linearity performance.

Fig. 11 depicts the evolution of  $IIP_3$  versus  $g_{m3}$  with and without the neutralizing capacitor  $C_4$ . As the bandwidth extension technique results in a 3–4 dB higher boosting gain (Fig. 7) it logically degrades the LNA  $IIP_3$  by almost the same factor. The use of  $C_4$  is still necessary since otherwise the LNA does not meet  $> 2$  GHz bandwidth. Ideally, a design point is chosen to simultaneously minimize the noise at an acceptable  $IIP_3$  value having an  $S_{11}$  lower than  $-10$  dB. Because of the differential operation the simulated  $IIP_2$  is found to be as high as  $+13.7$  dBm.

### F. Stability

Given the multiple cross-connections and feedbacks in the circuit (crossing of the sources, CCC on  $M_3$  gate,  $C_4$  neutralizing capacitors) the stability must be investigated. Two different points are addressed in this section. The first one is related to the DC biasing scheme which requires a close-loop control for good reliability. The second one concerns the effect of  $C_4$  on high-frequency stability.

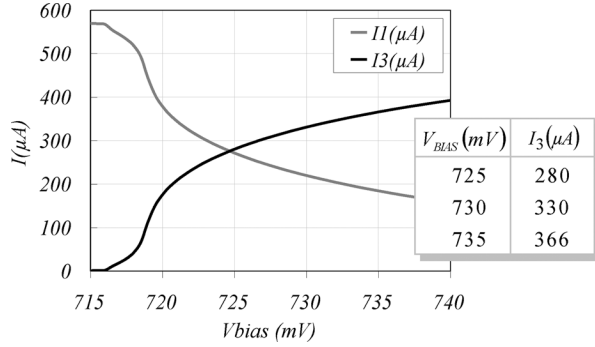


Fig. 12. Evolution of  $I_1$  &  $I_3$  bias current versus  $V_{BIAS}$  on  $M_3$  gate.

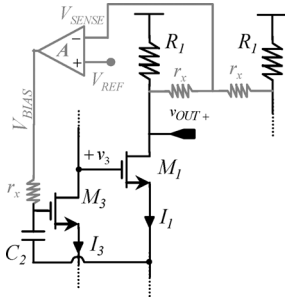


Fig. 13. DC loop feedback,  $V_{REF} = R_1 \cdot I_1 - R_{REF}$ .

1) *DC Feedback Stability*: The DC coupling between  $M_1$  gate and  $M_3$  drain makes the  $I_1/I_3$  ratio shown in Fig. 12 very sensitive to the biasing voltage on  $M_3$  gate ( $V_{BIAS}$ ). To control precisely the biasing for optimal noise and linearity operation, a DC feedback is necessary. The DC common mode at LNA output is sensed to generate  $V_{BIAS}$  with a DC comparator (Fig. 13). The comparator draws  $5 \mu A$  from the power supply, the phase margin of the total loop gain is  $60^\circ$ . The bandwidth of the comparator is kept very low and thus it does not introduce any loop instability.

2) *High Frequency Stability*: At high frequency the stability robustness is investigated by means of  $k$ -factor (20) [19], which indicates unconditional stability when  $k > 1$ .

$$k = \frac{1 - |S_{11}|^2 - |S_{22}|^2 + |S_{11}S_{22} - S_{12}S_{21}|^2}{2|S_{12}S_{21}|}. \quad (20)$$

$C_4$  is the most likely parameter to cause instability since the positive feedback it induces can strongly lower  $k$ -factor. In Fig. 14,  $C_4$  is swept till  $k$ -factor falls under unity for at least one frequency between 100 MHz to 10 GHz. The corresponding  $S_{11}$  curves are plotted in Fig. 15. It follows that the LNA is matched and unconditionally stable for  $C_4 < 30$  fF. Between 30 fF and 90 fF the LNA is no longer matched since  $S_{11} > -10$  dB but it still shows an unconditional stability. At 90 fF, the stability is no longer guaranteed at high frequency.

Finally  $C_4$  capacitor is set to 30 fF in order to reach a critical damped behavior. Even with strong technological variations on  $C_4$  the LNA will not exhibit stability problem.

### G. Circuit Implementation and Statistical Behavior

The geometry and biasing of the designed LNA is summarized in Table V. The output loads are somewhat high given the

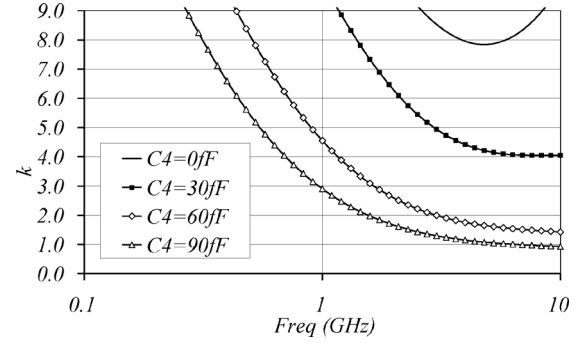


Fig. 14.  $k$ -factor between 0.1 GHz and 10 GHz for  $C_4 = 0$  fF, 30 fF, 60 fF, 90 fF.

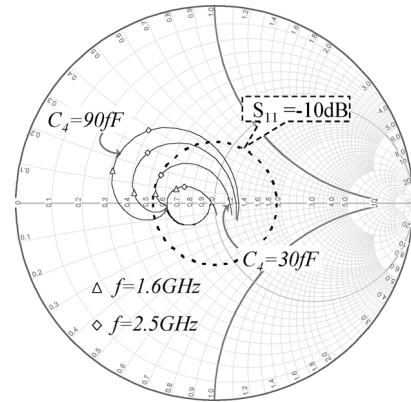


Fig. 15. Simulated input reflection coefficient  $S_{11}$  for  $C_4 = 0$  fF, 30 fF, 60 fF and 90 fF.

TABLE IV  
EFFECT OF  $C_4$  ON BANDWIDTH AND GAIN PEAKING.

$C_4$ (fF)	$\xi$	BW <sub>-3dB-SIM</sub> (GHz)	Gain Peaking(dB)
10	0.98	1.99	Under-damped
30	0.710	2.63	+0.2
60	0.49	2.66	+1.01

desired voltage gain of  $\sim 20$  dB. The power consumption is reduced to 1.32 mW (biasing excluded) for the whole circuit. The obtained NF is 4 dB. The robustness of the design from Table V versus technological variation is investigated through Monte Carlo analysis. Over 500 runs, both technological process deviations and in-wafer device mismatches are considered. PVT variations are simulated on all LNA components, including  $C_4$  capacitor. Mean ( $\mu$ ) and standard deviation ( $\sigma$ ) of the LNA metrics are given in Table VI.

Because of the high gain and the low power consumption, the linearity is the most likely metric to vary. The rest of the metrics appear reliable versus technological variations.

## IV. EXPERIMENTAL RESULTS

The proposed LNA has been implemented in ST-Microelectronics CMOS 0.13  $\mu m$ -GP process. The implemented design is described in Table V and the differential LNA draws 1.1 mA from a 1.2 V power supply. The active area is  $83 \times 83 \mu m^2$  ( $\sim 0.007$  mm<sup>2</sup>) of a 1.44 mm<sup>2</sup> pad-limited test-chip (Fig. 16) dedicated for on-wafer-probe measurement. No RF-specific process

TABLE V  
IMPLEMENTED DESIGN OF THE CGAB LNA.

	Main CG amp.	$G_m$ -boosting CG amp.	
Size & Bias	$(W/L)_1=(18/0,13)\mu\text{m}$ $R_1=700$ $V_{OV}\approx 40\text{mV}$ $I_1=220\mu\text{A}$ $C_L=50\text{fF}$ (25fF diff)	$(W/L)_3=(18/0,13)\mu\text{m}$ $(W/L)_4=(10/0,13)\mu\text{m}$ $R_3=1500$ $V_{OV}\approx 55\text{mV}$ $I_3=330\mu\text{A}$ $C_2=500\text{fF}$ $C_4=32\text{fF}$	
Small Signal.	$g_{m1}=3.5\text{mS}$ $g_{ds1}=214\mu\text{S}$ $c_{gs1}=13\text{fF}$ $c_{gd1}=9\text{fF}$	$g_{m3}=4.6\text{mS}$ $g_{ds3}=345\mu\text{S}$ $g_{ds4}=230\mu\text{S}$ $c_{gs3}=13\text{fF}$ $c_{gd3}=9\text{fF}$ $c_{v3}\approx 20\text{fF}$	
$G_v$ (dB)	$NF_{SIM}$ (dB)	$S_{11}$ (dB)	$IIP_3$ (dBm)
23.0	4.5	-10.9	-14.3

TABLE VI  
500 RUNS MONTE CARLO STATISTICAL DISTRIBUTIONS.

$I_{LNA}(\mu\text{A})$	$G_v^*$ (dB)	$NF_{SIM}$ (dB)	$S_{11}$ (dB)	$IIP_3$ (dBm)
$\mu=551$	$\mu=23.4$	$\mu=4.5$	$\mu=-10.9$	$\mu=-14.3$
$\sigma=10$	$\sigma=0.4$	$\sigma=0.56$	$\sigma=0.47$	$\sigma=1.05$

\* : The voltage gain  $G_v$  value is extracted at 2.45GHz for each run result

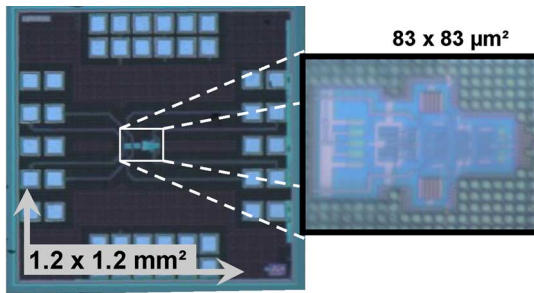


Fig. 16. Micrograph of the measured LNA and area of the core circuit.

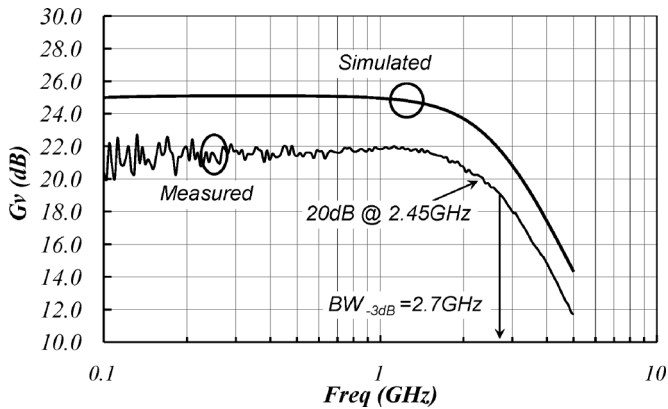


Fig. 17. Measured gain of the proposed CGAB LNA.

options like MIM capacitor or extra thick metals were used. For test purposes, the LNA is loaded with an output buffer, which consumes 5.5 mA using a dedicated power supply. It isolates the LNA output from the testing apparatus. The designed buffer shows an input parasitic capacitor which is close to the 50 fF  $C_L$  capacitor assumed before. A stand-alone version of this testing buffer is added next to the LNA for gain de-embedding purposes. The buffer  $IIP_3$  (+10 dBm) and its NF (7 dB) do not affect the measurements of the LNA  $IIP_3$  and NF. The gain and input matching measurement of the differential circuit are performed on a 4-port VNA providing true differential-mode S-parameters.

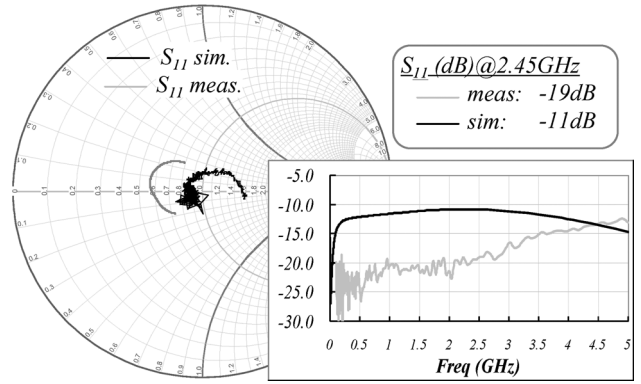


Fig. 18. Measured and simulated  $S_{11}$  of the CGAB LNA.

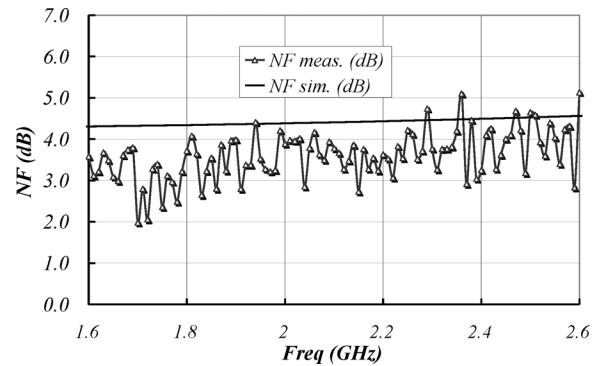


Fig. 19. Measured NF of proposed CGAB LNA.

Other measurements like NF and  $IIP_3$  require extra off-chip  $180^\circ$  couplers for single-to-diff conversions. The bandwidth of these couplers is limited from 1.5 GHz to 3 GHz. Measurements are compared to post-layout simulations with layout parasites of the core LNA circuit. The measured gain is depicted in Fig. 17. It shows a significant drop of almost 3 dB which has been identified to be caused by long-length RF input lines that exhibit a parasitic series inductance. The reduced boosting gain logically improves the measured  $S_{11}$  as shown in Fig. 18. The NF can be only measured in the working bandwidth of the hybrid couplers. Couplers with reduced bandwidth are preferred since they offer lower insertion losses. NF measurement is presented in Fig. 19. A significant fluctuation is observed in the NF plot because of the low gain of the chain. Indeed, the buffer losses reduce the accuracy of the measurement. However, Fig. 19 exhibits an average value around 4 dB. The measured  $ICP_{-1}$  dB and the  $IIP_3$  at 2.45 GHz are shown in Fig. 20. They are performed with a two-tone test at 2.45 GHz with 5 MHz tone spacing. Because of the gain drop, the LNA exhibits an improved  $IIP_3$  of 2 dB compared to simulation. The compression point is not surprisingly quite low given the low bias current of the LNA.

Table VII presents recently published low power LNAs. A Figure of Merit (FoM) defined in (21) is introduced for comparison purposes. The circuit area ( $A[\text{mm}^2]$ ) has been added in (21) to provide a fair comparison with non-inductorless LNAs ([1]–[3]). In Table VII, among the circuits that exhibit a FoM close to 100 dB, our circuit is the less consuming. We moreover



TABLE VII  
COMPARISON WITH PUBLISHED LOW POWER LNA.

Ref. Tech.	BW (GHz)	G <sub>v</sub> or S <sub>21</sub> (dB)	NF (dB)	IIP <sub>3</sub> (dBm)	P <sub>DC</sub> (mW)	Area (mm <sup>2</sup> )	FOM (dB)
[1] 0.13 μm	2.45	14.6 (S <sub>21</sub> )	3.8	-12	0.12† (0.6V)	0.63 *	77.90
[2] 0.18 μm	0.3-0.92	21	2-4	-3.2	3.6	0.33 **	68.79
[3] 0.18 μm	5.8	9.4 (S <sub>21</sub> )	2.5	+7.6	3.42 †	0.610 *	95.66
[4] 0.13 μm	0.1-0.9	13 (S <sub>21</sub> )	4	-10.2	0.72	0.268	62.39
[5] 0.18 μm	9.6	24 (S <sub>21</sub> )	4	-11.3	18	0.115 *	71.14
[6] 0.13 μm	3.8	19	3.4	-4.2	5.7 †	0.0252	97.56
[8] 90 nm	7	22	2.9	-8.5	12 †	0.012	99.18
[10] 0.18 μm	0.4-0.9	20.7	2.95	-16 ‡	0.385 (0.5V)	0.07 **	79.42
[11] 90 nm	6	16.5	2.5	-10	9.2 †	0.0017	109.90
[20] 0.13 μm	0.01-1.4	22	7	-17	0.9 †	0.03	70.23
[21] 90 nm	0.1-1.66	10.5 (S <sub>21</sub> )	5.9	-4.5	0.425†	Sim.	-
[22] 0.13 μm	0.2-3.8	11.2	2.85	-2.7	1.9	Sim.	-
<b>T.W</b> <b>0.13μm</b>	<b>0.1-2.7</b>	<b>20</b>	<b>4.0</b>	<b>-12</b>	<b>1.32</b>	<b>0.007</b>	<b>101.72</b>

† Single ended input LNA. \* Use on-chip inductor \*\*Use off-chip inductor ‡Obtained from authors of [10]

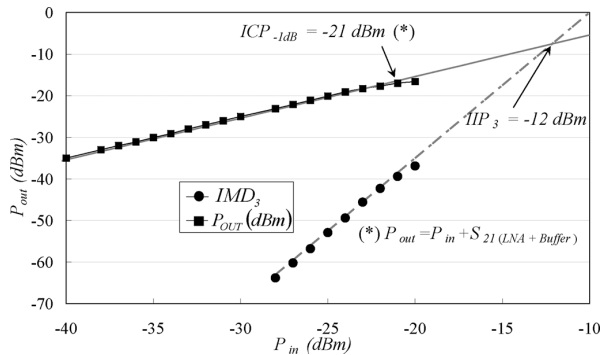


Fig. 20. Measured IIP3 and ICP-1 dB of proposed CGAB LNA.

offer a high-IIP<sub>2</sub> fully-differential circuit robust to common mode noise

$$FoM = 20 \log_{10} \left( \frac{BW [\text{GHz}] \cdot G_V [\text{lin.}] \cdot IIP_3 [\text{mW}]}{P_{DC} [\text{mW}] \cdot (F - 1) \cdot A [\text{mm}^2]} \right). \quad (21)$$

## V. CONCLUSION

A doubly-g<sub>m</sub>-boosted CG LNA circuit is presented. It achieves a power consumption of 1.32 mW for fully differential operation. The LNA design makes use of both active and passive g<sub>m</sub>-boosting effects in order to reach a 4 dB NF and a large voltage gain at milliwatt range P<sub>DC</sub>. Tradeoff between noise and linearity has been discussed. The LNA shows good stability as well as good robustness versus technological

variations. The measured circuit shows good performances compared to other low P<sub>DC</sub> LNAs. Inductorless implementation result in a silicon area of 0.007 mm<sup>2</sup>.

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